

Notice of References Cited	Application/Control No. 09/995,641	Applicant(s)/Patent Under Reexamination WENDELUP, HEINO	
	Examiner Eric Elcenko	Art Unit 2643	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0085263	04-2005	Kim et al.	455/556.1
*	B	US-6,915,119	07-2005	Konishi, Masahiro	455/127.1
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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